

# Scope of Accreditation

(Measurement Method)

Accreditation Number: VLAC-023

Expiration Date: March 26, 2025

[Name of Laboratory]

**Mitsubishi Electric Engineering Co., Ltd. EMC East Japan Center**

[Test site name]

**EMC East Japan Center**

[Test site Address]

**325 Kamimachiya, Kamakura-shi, Kanagawa 247-8520, JAPAN**

[Measurement Methods]

## Emission test

**Radiated disturbance : Enclosure Port**

**Disturbance electric field test**

[Test condition] **On the reference ground plane, Measurement distance: 3 m / 10 m  
Measurement Frequency Range: 30 MHz - 1 GHz**

[Test condition] **Quasi Free Space, Measurement Frequency Range: 1 GHz - 18 GHz**

**Disturbance magnetic field strength measurement** [Test condition] **Loop Antenna**

**Disturbance power measurement** [Test condition] **Absorbing Clamp**

**Conducted disturbance Measurement: AC mains port / DC power line port**

**Voltage Measurement** [Test condition] **AMN, High impedance probe**

**Conducted disturbance Measurement: Telecommunication port**

**Voltage Measurement** [Test condition] **ISN, AAN**

**Current Measurement** [Test condition] **Current probe**

## Immunity test

**Electro static discharge test** **Contact discharge, Air discharge, Indirect discharge**

**Radiated electromagnetic field strength** **Measurement Frequency Range: 80 MHz - 6 GHz**

**Electrical fast transient/burst (EFT/B)**

**Mains port, Telecommunication/Signal port**

**Immunity to transient disturbances conducted along supply lines**

**Surge** **Mains port, Telecommunication/Signal port**

**RF conducted interference**

**Mains port measurement frequency range: 150 kHz - 100 MHz**

**Telecommunication/Signal port measurement frequency range: 150 kHz - 100 MHz**

**Radiated magnetic field**

**Interruptions and Voltage variations**

## Harmonic current

**Harmonic current test**

**Voltage changes, Voltage fluctuations and Flicker test**

## Telecommunication equipment performance 2

**Magnetic field strength** [Test condition] **Magnetic probe**

**Electric field strength** [Test condition] **Electric field probe**

**Voluntary EMC Laboratory Accreditation Center Inc.**

# Scope of Accreditation

(Test standards)

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[Test standards]

## **Emission test**

VCCI Technical Requirements: VCCI-CISPR 32, J55014-1 :2015

Technical requirements under the Electrical Appliances and Materials safety Act appendix 10 Chapter 4 and Chapter5

FCC 47 CFR Part 15 Subpart B: ANSI C63.4-2014 (up to 18 GHz)

FCC 47 CFR Part 18: FCC MP-5(1986) (up to 18 GHz)

CISPR 11:2015+A1:2016, CISPR 14-1:2020, CISPR 32:2015+A1:2019

EN 55011:2016+A1:2017, EN 55014-1:2017+A11:2020, EN 55032:2015

IEC 61000-6-3:2006+A1:2010, EN 61000-6-3:2007+A1:2011

IEC 61000-6-4:2018, EN IEC 61000-6-4:2019, EN 12015:2014

IEC 61326-1:2020, EN 61326-1:2013, JIS C 61326-1:2022

IEC 60601-1-2:2014+A1:2020, EN 60601-1-2:2015+A1:2021, JIS T 0601-1-2:2018

AS CISPR 11:2017, AS CISPR 14.1:2018, AS/NZS CISPR 22:2006, AS/NZS CISPR 32:2015

AS/NZS 61000.6.3:2012, AS/NZS 61000.6.4:2012

ICES-003(Isse 7), CNS 13438:2006, CNS 13783-1:2013

KS C 9811:2019, KS C 9610-6-4:2017, GB 4343.1:2018, GB/T 9254:2008

## **Immunity test**

IEC 61000-4-2:2008, IEC 61000-4-3:2006+A1:2007+A2:2010, IEC 61000-4-4:2012

IEC 61000-4-5:2014+A1:2017, IEC 61000-4-6:2013, IEC 61000-4-8:2009

IEC 61000-4-11:2004+A1:2017, IEC 61000-4-39:2017\*<sup>1</sup>

EN 61000-4-39:2017\*<sup>2</sup>

KS C 9610-4-2:2017, KS C 9610-4-3:2017, KS C 9610-4-4:2020, KS C 9610-4-5:2020

KS C 9610-4-6:2020, KS C 9610-4-8:2017, KS C 9610-4-11:2020

\*<sup>1</sup>: Only the items for the magnetic field immunity required by IEC 60601-1-2 are applied.

\*<sup>2</sup>: Only the items for the magnetic field immunity required by EN 60601-1-2 are applied.

CISPR 14-2 :2015, CISPR 35:2016\*<sup>3</sup>

EN 55014-2:2015, EN 55035:2017\*<sup>3</sup>

IEC 61000-6-1:2016, IEC 61000-6-2:2016

EN 61000-6-1:2007, EN 61000-6-2:2005, EN 12016:2013

JIS C 61000-6-1:2019, JIS C 61000-6-2:2019

IEC 61326-1:2020, EN 61326-1:2013, JIS C 61326-1:2022

IEC 60601-1-2:2014+A1:2020, EN 60601-1-2:2015+A1:2021, JIS T 0601-1-2:2018

AS/NZS CISPR 14.2:2013, AS/NZS CISPR 24:2013

AS/NZS 61000.6.1:2006, AS/NZS 61000.6.2:2022

KS C 9610-6-2:2019, GB 4343.2:200

\*<sup>3</sup>: Excluding Annex A, Annex E, Annex F, Annex G and Annex H.

**Harmonic Test in Public Low Voltage Systems**

IEC 61000-3-2:2014, EN 61000-3-2:2014, IEC 61000-3-3:2013, EN 61000-3-3:2013

IEC 61000-3-11:2017, EN 61000-3-11:2000, IEC 61000-3-12:2011, EN 61000-3-12:2011

JIS C 61000-3-2 :2019

AS/NZS 61000.3.2:2013, AS/NZS 61000.3.3:2012, AS/NZS 3200.1.2 :2005

IEC 61000-6-3:2006+A1:2010, EN 61000-6-3:2007+A1:2011

GB 17625.1:2012

IEC 61326-1:2020, EN 61326-1:2013, JIS C 61326-1:2022

IEC 60601-1-2:2014+A1:2020, EN 60601-1-2:2015+A1:2021, JIS T 0601-1-2:2018

**Telecommunication equipment performance 2**

IEC 62233:2005, EN 62233:2008

**Voluntary EMC Laboratory Accreditation Center Inc.**

The laboratory is only accredited for testing activities outlined within the test methods listed above.  
If test standards do not include the edition, it means the latest one at the date of renewal (3.27,2023).